



**DEFENSE LOGISTICS AGENCY**  
LAND AND MARITIME  
POST OFFICE BOX 3990  
COLUMBUS, OH 43218-3990

September 11, 2018

Mr. Dennis Wojtkiewicz  
Cirtech Inc.  
250 E. Emerson Ave.  
Orange, CA. 92865-3303

Dear Mr. Wojtkiewicz:

RE: Laboratory Suitability Status, MIL-PRF-31032, MIL-PRF-55110, MIL-PRF-50884; CAGE Code:  
8K616; CN064253, VQE-18-033026

This office has received your correspondences which address corrective actions taken regarding the concerns from your most recent facilities audit. Based on this information and the sample audit on January 30 through February 1, 2018, your facility is considered suitably equipped to perform qualification, lot conformance, and periodic conformance inspection to Department of Defense Performance Specifications MIL-PRF-31032 and MIL-PRF-55110 for the following test methods:

**IPC-TM-650 Test Methods Manual:**

(per internal procedures)

Method 2.1.1	Microsectioning – Manual and Semi or Automatic
Method 2.1.8	Workmanship
Method 2.2.1	Mechanical Dimensional Inspection
Method 2.2.2	Optical Dimensional Inspection
Method 2.2.5	Dimensional Inspections Using Microsections
Method 2.2.6	Hole Size Measurement, Drilled
Method 2.2.7	Hole Size Measurement, Plated
Method 2.4.1	Plating Adhesion
Method 2.4.22	Bow and Twist
Method 2.4.28.1	Solder Mask Adhesion

**MIL-PRF-31032 Solder Float Solderability (in accordance with appendix H of MIL-PRF-31032C)**

(per internal procedures)

**MIL-PRF-31032 Resistance to Soldering Heat (solder float thermal in accordance with condition A of appendix F of MIL-PRF-31032C)**

(per internal procedures)

**MIL-PRF-31032/1, /2 Marking Adhesion**

(per internal procedures)

**MIL-PRF-31032/1, /2 Electrical Test Methods (probe testing)**

(per internal procedures)

Paragraph 4.7.5.1, Continuity

Paragraph 4.7.5.2, Isolation

**Auto Optical Inspection (AOI) of Inner Layers**

(per internal procedures)

**Ionizable Detection of Surface Contamination – alternative method using Zero Ion equipment**

(per internal procedures)

**Nondestructive Thickness Testing for Conductor Plating and Finish (CMI-900 XRF Analyzer)**  
(per internal procedures)

**Controlled Impedance Testing**  
(per internal procedures)

Any additional and/or alternative test methods implemented shall be approved by the Technical Review Board (TRB) and concurrently reported to the Qualifying Activity. Please contact Mr. Robert Puckett, DLA Land and Maritime-VQE, at (614) 692-0625 or [vqe.rp@dla.mil](mailto:vqe.rp@dla.mil) with any questions concerning this laboratory suitability.

Sincerely,

RAYMOND L KOLONCHUK  
Chief  
Electronic Devices Branch